




<b>Search Notes</b>  	Application/Control No.  10816860	Applicant(s)/Patent Under Reexamination  SHIN, SUNG SU
	Examiner Haney, Richale L	Art Unit 3765

Notes	Date	Examiner
See EAST printout	10/23/2006	RLH
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<b><i>Interference Searched</i></b>  	Application/Control No.  10816860	Applicant(s)/Patent Under Reexamination  SHIN, SUNG SU
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EAST .clm. search		10/23/2006	RLH

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2	181,183,184,171,200.1	10/23/2006	RLH

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